Test Org.*	Device	Function	Technology	Mfr.	Effective SEU LET* Threshold	Device Xsection (cm^2)	Bits Tested	Bit Xsection (cm^2)	Test Date	LUth	LU Xsection (cm^2)	Fac.	Remarks 23-Aug-99
		DAC (8-bit)											
	Note: Entries in **RED** indicate data added since the 1997 Compendium.												
BREL	AD558		Bipolar-IIL	ADI	<<5	2.0E-04			Feb-92				
JPL	AD7225TQ		LCCMOS	ADI					Jan-97	>62		TAM	Nichols. 1961 MeV Xe at 45° C. Runs with PIC16674A µController.
MM	CA3338AD		CMOS/TTL	HAR	>119				May-93				
GSFC	DAC 08AQ		Bipolar	PMI	~3.5	2.0E-02			Jul-94				
S^3	DAC8408		CMOS	PMI	45	4.0E-05			Jan-92				
GSFC	**DAC8800**	**Octal, serial input**	**Bipolar**	**ADI**	**>80**				**Apr-97**	**>80**			**LaBel, EEE Links, Vol. 3, No. 1, Mar 97, pg 5.**
Legend													
	Manufacturers: ADI - Analog Devices, Inc; HAR - Harris Corp; PMI - Precision Monolithic, Inc												
	Test Organizations			**Radiation Test Facilities**									
	BREL - Boeing Radiation Effects Laboratory, Seattle, WA			TAM - Texas A&M University Cyclotron Institute, College Station, TX									
	GSFC - Goddard Space Flight Center, Greenbelt, MD												
	JPL - Jet Propulsion Laboratory, Pasadena, CA												
	MM - Martin Marietta Aerospace, Valley Forge, PA												
	S^3 - S-Cubed, San Diego, CA												